| Notice of Allowability | Application No. | Applicant(s) | |
|---|---|--|------------------------------|
| | 09/198,849 KANEYAMA, YOSHINOBU | | HINOBU |
| | Examiner | Art Unit | |
| | M. Alexandra Elve | 1725 | <u> </u> |
| The MAILING DATE of this communication appeal All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT R of the Office or upon petition by the applicant. See 37 CFR 1.313 | (OR REMAINS) CLOSED ir or other appropriate commu IGHTS. This application is s | n this application. If not inclu unication will be mailed in du | ded e course. THIS |
| 1. This communication is responsive to <u>2/4/04</u> . | | | |
| 2. The allowed claim(s) is/are <u>10-19,21,22 and 25-52</u> . | | | |
| 3. The drawings filed on 24 November 1998 are accepted by | the Examiner. | | |
| 4. Acknowledgment is made of a claim for foreign priority una) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority documents have International Bureau (PCT Rule 17.2(a)). * Certified copies not received: Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. 5. A SUBSTITUTE OATH OR DECLARATION must be submarted in NFORMAL PATENT APPLICATION (PTO-152) which give 6. CORRECTED DRAWINGS (as "replacement sheets") mual (a) including changes required by the Notice of Draftsper 1) hereto or 2) to Paper No./Mail Date (b) including changes required by the attached Examiner Paper No./Mail Date Identifying indicia such as the application number (see 37 CFR each sheet. Replacement sheet(s) should be labeled as such in | e been received. e been received in Application ocuments have been received of this communication to file MENT of this application. Initial Note the attached EXA es reason(s) why the oath of st be submitted. son's Patent Drawing Review. 's Amendment / Comment of 1.84(c)) should be written on the state of the should be written on | on No d in this national stage applicate a reply complying with the read AMINER'S AMENDMENT or declaration is deficient. W (PTO-948) attached In the Office action of the drawings in the front (not the control of the drawings in the front the the control of the drawings in the front (not the control of the drawings in the front (not the control of the drawings in the front (not the control of the drawings in the front (not the control of the drawings in the front (not the control of the drawings) | equirements NOTICE OF |
| 7. DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT | | | . Note the |
| Attachment(s) 1. Notice of References Cited (PTO-892) 2. Notice of Draftperson's Patent Drawing Review (PTO-948) 3. Information Disclosure Statements (PTO-1449 or PTO/SB/Paper No./Mail Date 4. Examiner's Comment Regarding Requirement for Deposit of Biological Material | 6. Interview S Paper No. 7. Examiner's | nformal Patent Application (Poliummary (PTO-413), Mail Date <u>2/25/04</u> . Amendment/Comment Statement of Reasons for A | ŕ |
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Application/Control Number: 09/198,849

Art Unit: 1725

EXAMINER'S AMENDMENT

The application has been amended as follows:

In claim 52, line 13, after "are in the", insert – liquid.--.

Claims 10-19, 21-22 & 25-52 are allowed.

The following is an examiner's statement of reasons for allowance: the prior art does not teach that the center of the device electrode is not aligned with the center of the substrate electrode while the device is partially submerged in a liquid.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to M. Alexandra Elve whose telephone number is 571-272-1173. The examiner can normally be reached on 6:30-3:00 Monday to Friday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Tom Dunn can be reached on 571-272-1171. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Examiner 5 Amendment.

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positioning said plurality of respective device electrodes so as to contact said opposite surface of said respective solder bumps such that the centers of said plurality of respective device electrodes are not aligned with the respective centers of said plurality of substrate electrodes while said device is at least partially submerged in said liquid;

aligning the centers of said plurality of respective device electrodes with the respective centers of said plurality of substrate electrodes by surface tension of said respective solder bumps when said respective solder bumps are melted and while said device is at least partially submerged in said liquid and at least partially supported by a buoyant force thereby joining said plurality of substrate electrodes and said plurality of respective device electrodes to each other; and

solidifying said respective solder bumps.

52. (Previously Presented) A method of joining a device to a substrate, the substrate having a plurality of solder pieces electrically coupled to a plurality of substrate electrodes, the method comprising:

placing the substrate in a liquid;

melting the plurality of solder pieces to form a plurality of solder bumps while the substrate is in the liquid;

placing a device having a plurality of respective device electrodes on the plurality of solder bumps while the device is in the liquid such that the plurality of respective device electrodes are out of alignment with a respective substrate electrode of the plurality of substrate electrodes; and

melting the plurality of solder bumps so as to cause the plurality of respective device electrodes to align with the plurality of respective substrate electrodes while the device and the substrate are in the 194 id.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

February 25, 2004.

M. ÁLEXÁNDRA ELVE PRIMARY EXAMINER